



Application 09/914,081 Applicant Donald Dominic ARNONE et al. Filing Date April 23, 2002		OFGS File No P/25-267 Group Art Unit 2882					
APPLICANT'S ART CITATION (Use several sheets if necessary)							
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Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
PCH	US-5,789,750	08-1998	Nuss	250	338.1	RECEIVED JAN 28 2004 TECHNOLOGY CENTER R3700	
PCH	US-5,623,145	04-1997	Nuss	250	330		
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	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
PCH	WO 97/45747	12-1997	PCT				
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	1.	Fattinger, et al., "Point Source Terahertz Optics" Appl. Phys. Lett. 53(16), 17 October 1988, pp. 1480-1482.					
	2.	Fattinger et al., "Tetahertz Beams" Appl. Phys. Lett. 54 (6), 6 February 1989, pp. 490-492					
	3.	Mittleman, et al. "T-Ray Imaging" IEEE Journal of Selected Topics in Quantum Electronics, 2 (3), September 1996, pp. 679-692.					
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							

APPLICANT'S ART CITATION (Use several sheets if necessary)		Application		OFGS File No. P/25-267 #8									
		Applicant Donald Dominic ARNONE et al.											
		Filing Date		Group Art Unit									
U.S. PATENT DOCUMENTS													
Examiner Initial	Document Number				Date								
					Name								
					Class								
					Sub-class								
					Filing Date If Appropriate								
FOREIGN PATENT DOCUMENTS													
	Document Number				Date								
					Country								
					Class								
					Sub-class								
					Translation								
					Yes	No							
PLN	0	8	4	1	5	4	8	05/13/98	Europe				
I	0	8	2	8	1	4	3	03/11/98	Europe				
I	0	7	2	7	6	7	1	08/21/96	Europe				
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